

FQD6N40C / FQU6N40C N-Channel QFET MOSFET 400 V, 4.5 A, 1.0 Ω

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

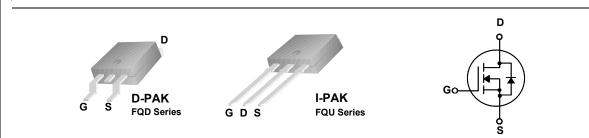
Features

+ 4.5 A, 400 V, ${\sf R}_{\sf DS(on)}$ = 1.0 Ω (Max) @V_{\sf GS} = 10 V, ${\sf I}_{\sf D}$ = 2.25 A

FQD6N40C / FQU6N40C N-Channel MOSFET

March 2013

- Low Gate Charge (Typ. 16 nC)
- Low Crss (Typ. 15 pF)
- 100% Avalanche Tested



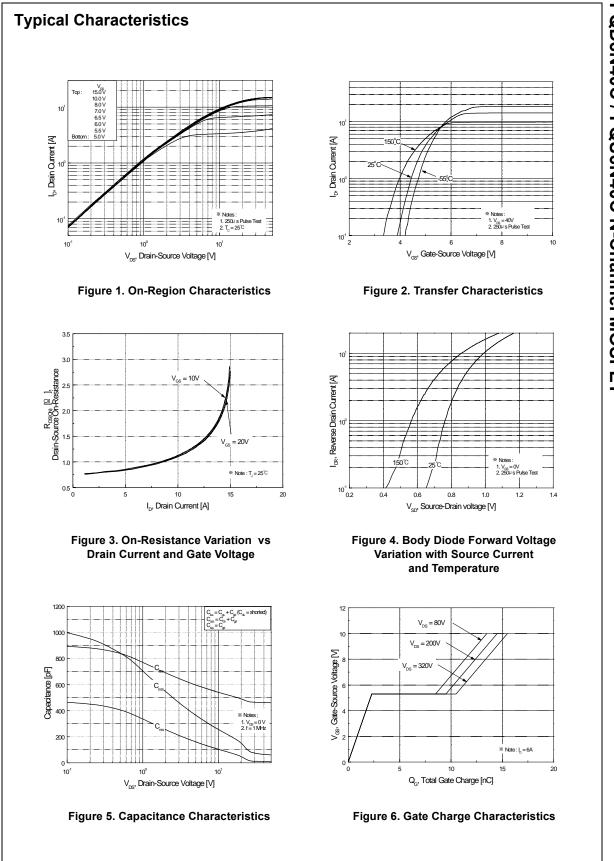
Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD6N40C / FQU6N40C	Unit
V _{DSS}	Drain-Source Voltage		400	V
I _D	Drain Current - Continuous (T _C = 25°	(O°	4.5	Α
	- Continuous (T _C = 10	D°C)	2.7	А
I _{DM}	Drain Current - Pulsed	(Note 1)	18	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	270	mJ
I _{AR}	Avalanche Current	(Note 1)	4.5	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.8	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P _D	Power Dissipation $(T_A = 25^{\circ}C)^*$		2.5	W
	Power Dissipation (T _C = 25°C)		48	W
	- Derate above 25°C		0.38	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

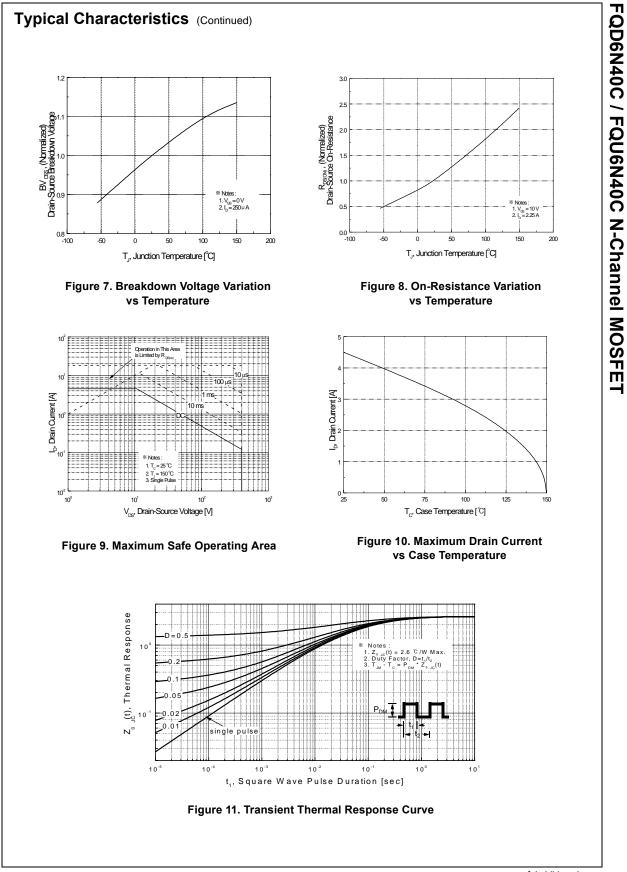
Thermal Characteristics

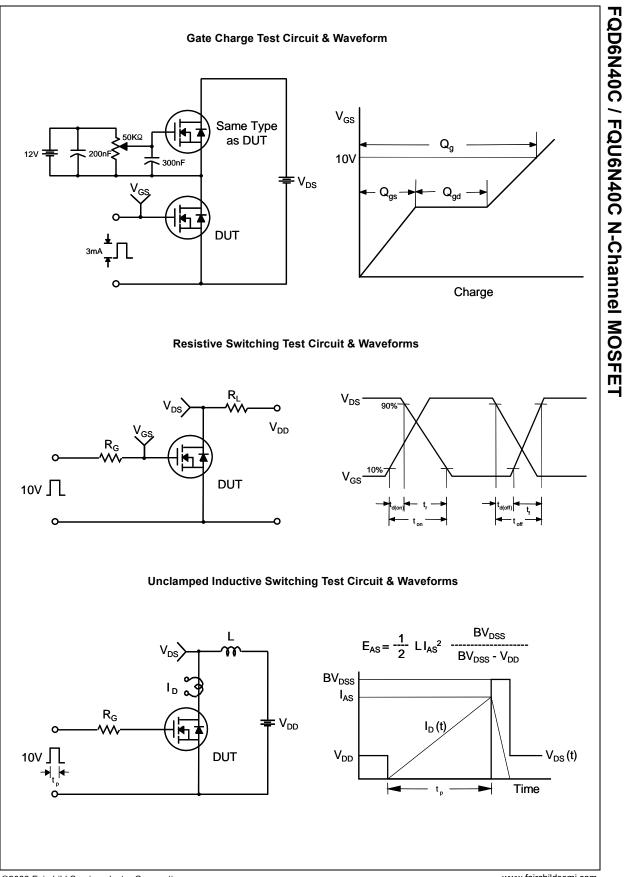
Symbol	Parameter	Тур	Max	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case		2.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient.*		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient.		110	°C/W

Parameter	Test Conditions	Min	Тур	Мах	Unit
racteristics					
Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA				V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		0.54		V/°C
Zara Cata Valtaga Drain Current	$V_{DS} = 400 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA
Zero Gale voltage Drain Current	$V_{DS} = 320 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$			10	μA
Gate-Body Leakage Current, Forward				100	nA
Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ractoristics					
	$V_{DS} = V_{GS}$. $I_{D} = 250 \mu A$	2.0		4.0	V
Static Drain-Source		2.0			Ω
On-Resistance			0.85	1	52
Forward Transconductance	$V_{DS} = 40 \text{ V}, \text{ I}_{D} = 2.25 \text{ A}$ (Note 4)		4.7		S
ic Charactoristics					
			480	625	pF
					p. pF
					pF
Turn-On Rise Time	$V_{DD} = 200 \text{ V}, \text{ I}_{D} = 6\text{A},$ $R_{G} = 25 \Omega$		65	35 140	ns
	$V_{DD} = 200 \text{ V}, \text{ I}_{D} = 6\text{A},$				ns
Turn-Off Delay Time	116 - 20 22		21	55	ns
Turn-Off Fall Time	(Note 4, 5)		38	85	ns
Total Gate Charge	$V_{DS} = 320 \text{ V}, I_{D} = 6\text{A},$		16	20	nC
Gate-Source Charge			2.3		nC
Gate-Drain Charge	(Note 4, 5)		8.2		nC
ourse Diede Cheresteristics o	ad Maximum Datinga				1
				45	A
					A
Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 4.5 A$			1.4	V
course preas r ormana voltage					ns
Reverse Recovery Time	$V_{GS} = 0 V, I_{S} = 6 A,$		230		
	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse racteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance ic Characteristics Input Capacitance Output Capacitance Output Capacitance Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Fall Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge ource Diode Characteristics an Maximum Continuous Drain-Source Dio	Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu$ A, Referenced to 25°CZero Gate Voltage Drain Current $V_{DS} = 400 \ V, V_{GS} = 0 \ V$ Gate-Body Leakage Current, Forward $V_{GS} = 320 \ V, T_C = 125^{\circ}C$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \ V, V_{DS} = 0 \ V$ Gate-Body Leakage Current, Reverse $V_{GS} = -30 \ V, V_{DS} = 0 \ V$ racteristics $V_{GS} = -30 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \ \mu$ AStatic Drain-Source On-Resistance $V_{GS} = 10 \ V, I_D = 2.25A$ On-Resistance $V_{DS} = 40 \ V, I_D = 2.25A$ Forward Transconductance $V_{DS} = 25 \ V, V_{GS} = 0 \ V,$ Input Capacitance Reverse Transfer Capacitance $V_{DS} = 25 \ V, V_{GS} = 0 \ V,$ furn-On Delay Time Turn-On Rise Time $V_{DD} = 200 \ V, I_D = 6A,$ $R_G = 25 \ \Omega$ Turn-Off Fall Time Turn-Off Fall Time $V_{DS} = 320 \ V, I_D = 6A,$ $V_{GS} = 10 \ V$	Breakdown Voltage Temperature CoefficientID $250 \ \mu$ A, Referenced to 25° CID $I_D = 250 \ \mu$ A, Referenced to 25° CZero Gate Voltage Drain Current $V_{DS} = 400 \ V, V_{GS} = 0 \ V$ Gate-Body Leakage Current, Forward $V_{GS} = 30 \ V, V_{DS} = 0 \ V$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \ V, V_{DS} = 0 \ V$ racteristics $V_{GS} = -30 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{DS} = V_{GS}, \ I_D = 250 \ \mu$ A2.0Static Drain-Source On-Resistance $V_{GS} = 10 \ V, \ I_D = 2.25 \ A$ Forward Transconductance $V_{DS} = 40 \ V, \ I_D = 2.25 \ A$ Input Capacitance Reverse Transfer Capacitance $V_{DS} = 25 \ V, \ V_{GS} = 0 \ V, \ I_D = 2.25 \ A$ reverse Transfer Capacitance $V_{DS} = 25 \ V, \ V_{GS} = 0 \ V, \ I_D = 2.25 \ A$ Turn-On Delay Time Turn-On Rise Time $V_{DD} = 200 \ V, \ I_D = 6A, \ P_C \ R_G = 25 \ \Omega$ Turn-Off Fall Time $V_{DS} = 320 \ V, \ I_D = 6A, \ P_C $	$\begin{tabular}{ c c c c c } \hline Product Produ$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

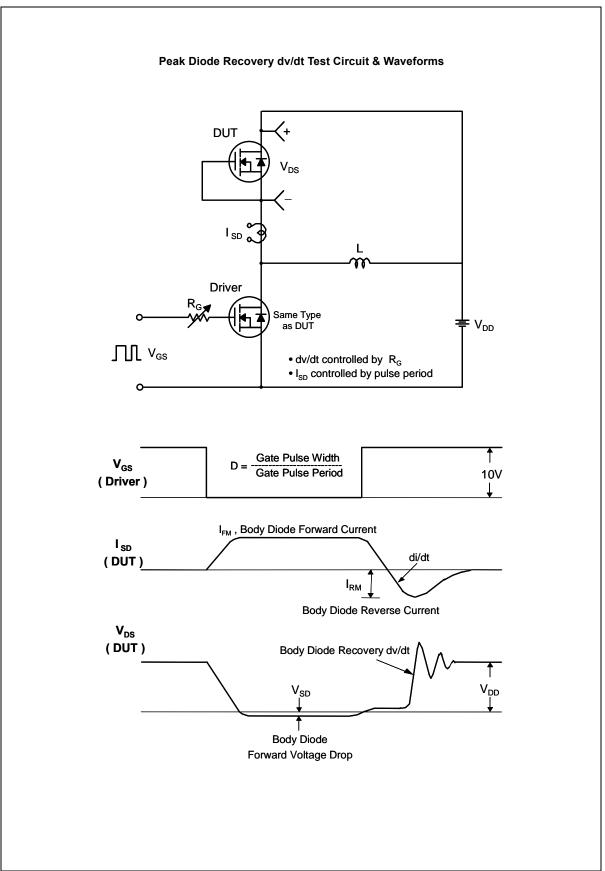


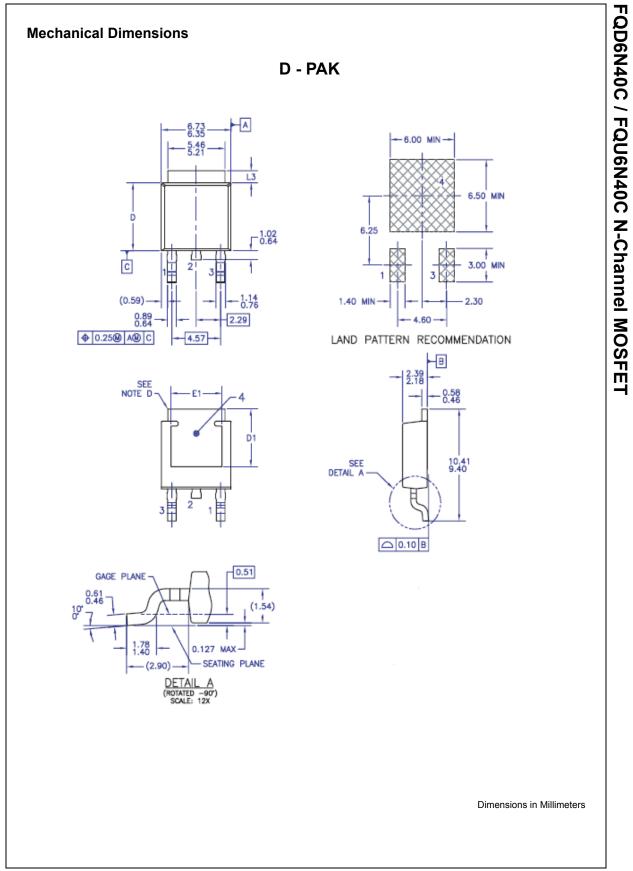
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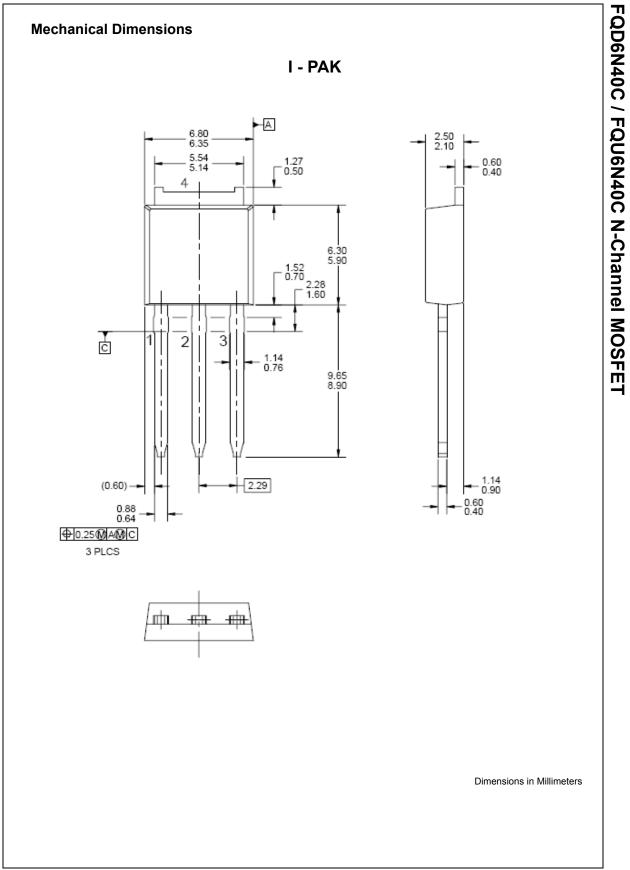


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